- State-of-the-Art BiCMOS Design Significantly Reduces ICCz
- ESD Protection Exceeds 2000 V

Per MIL-STD-883C, Method 3015

- Power-Up High-Impedance State
- 3-State Inverting Outputs
- Back-to-Back Registers for Storage
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Plastic and Ceramic 300-mil DIPs (JT, NT)


## description

The 'BCT544 octal registered transceiver contains two sets of D-type latches for temporary storage of data flowing in either direction. Separate latch-enable ( $\overline{\mathrm{LEAB}}$ or $\overline{\mathrm{LEBA}}$ ) and output-enable ( $\overline{\mathrm{OEAB}}$ or $\overline{\mathrm{OEBA}}$ ) inputs are provided for each register to permit independent control in either direction of data flow.

The A-to-B enable ( $\overline{\mathrm{CEAB}}$ ) input must be low in order to enter data from $A$ or to output data from B. If $\overline{C E A B}$ is low and $\overline{\mathrm{LEAB}}$ is low, the A-to-B latches are transparent; a subsequent low-to-high transition of LEAB puts the $A$ latches in the storage mode. With $\overline{\mathrm{CEAB}}$ and $\overline{\mathrm{OEAB}}$ both low, the 3 -state $B$ outputs are active and reflect the inverted data present at the output of the A latches. Data flow from $B$ to $A$ is similar, but requires using the $\overline{C E B A}$, $\overline{L E B A}$, and $\overline{O E B A}$ inputs.
The SN54BCT544 is characterized for operation over the full military temperature range of $-55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$. The SN74BCT544 is characterized for operation from $0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$.

## SN54BCT544... JT OR W PACKAGE <br> SN74BCT544 ... DW OR NT PACKAGE (TOP VIEW)



SN54BCT544... FK PACKAGE (TOP VIEW)


NC - No internal connection

FUNCTION TABLE $\dagger$

| INPUTS |  |  |  | OUTPUT |
| :---: | :---: | :---: | :---: | :---: |
| $\overline{\text { CEAB }}$ | $\overline{\text { LEAB }}$ | $\overline{\text { OEAB }}$ | A |  |
| $H$ | X | X | X | Z |
| L | X | H | X | Z |
| L | H | L | X | $\mathrm{B}_{0} \ddagger$ |
| L | L | L | L | H |
| L | L | L | H | L |

$\dagger$ A-to-B data flow is shown; B-to-A flow control is the same except that it uses CEBA, $\overline{\text { LEBA }}$, and $\overline{\text { OEBA }}$.
$\ddagger$ Output level before the indicated steady-state input conditions were established.

## logic symbol $\dagger$


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
logic diagram (positive logic)


Pin numbers shown are for the DW, JT, NT, and W packages.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted) $\dagger$

|  |  |  |
| :---: | :---: | :---: |
| Input voltage range: Control inputs (see Note 1) ...................................... 0.5 l , to 7 V |  |  |
| I/O ports (see Note 1) ......................................... -0.5 F C to 5.5 V |  |  |
|  |  |  |
|  |  |  |
| Input clamp current .................................................................. - 30 mA |  |  |
| Current into any output in the low state: SN54BCT544 .................................... 96.0 mA |  |  |
|  | SN74BCT544 | 128 mA |
| Operating free-air temperature range: | SN54BCT544 | $55^{\circ} \mathrm{C}$ to $125^{\circ} \mathrm{C}$ |
|  | SN74BCT544 | $0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$ |
| Storage temperature range |  | $65^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$ |

$\dagger$ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
NOTE 1: The input negative voltage rating may be exceeded if the input clamp-current rating is observed.
recommended operating conditions

|  |  | SN54BCT544 |  |  | SN74BCT544 |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | MIN | NOM | MAX | MIN | NOM | MAX |  |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage | 4.5 | 5 | 5.5 | 4.5 | 5 | 5.5 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | High-level input voltage | 2 |  |  | 2 |  |  | V |
| $\mathrm{V}_{\text {IL }}$ | Low-level input voltage |  |  | 0.8 |  |  | 0.8 | V |
| IIK | Input clamp current |  |  | -18 |  |  | -18 | mA |
| ${ }^{\text {IOH }}$ | High-level output current |  |  | -12 |  |  | -15 | mA |
| IOL | Low-level output current |  |  | 48 |  |  | 64 | mA |
| $\mathrm{T}_{\mathrm{A}}$ | Operating free-air temperature | -55 |  | 125 | 0 |  | 70 | ${ }^{\circ} \mathrm{C}$ |

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | TEST CONDITIONS |  | SN54BCT544 |  |  | SN74BCT544 |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP $\dagger$ | MAX | MIN | TYP† | MAX |  |
| $\mathrm{V}_{\text {IK }}$ | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$, | $\mathrm{I}=-18 \mathrm{~mA}$ |  |  | -1.2 |  |  | -1.2 | V |
| $\mathrm{V}_{\mathrm{OH}}$ | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$ | $\mathrm{IOH}=-3 \mathrm{~mA}$ | 2.4 | 3.3 |  | 2.4 | 3.3 |  | V |
|  |  | $\mathrm{OH}=-12 \mathrm{~mA}$ | 2 | 3.2 |  |  |  |  |  |
|  |  | $1 \mathrm{OH}=-15 \mathrm{~mA}$ |  |  |  | 2 | 3.1 |  |  |
|  | $\mathrm{V}_{\mathrm{CC}}=4.75 \mathrm{~V}$, | $\mathrm{IOH}^{\prime}=-3 \mathrm{~mA}$ |  |  |  | 2.7 |  |  |  |
| VOL | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$ | $\mathrm{IOL}=48 \mathrm{~mA}$ |  | $0.38 \quad 0.55$ |  |  |  |  | V |
|  |  | $\mathrm{IOL}=64 \mathrm{~mA}$ |  |  |  |  | 0.42 | 0.55 |  |
| 1 | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{I}}=5.5 \mathrm{~V}$ |  |  | 0.4 |  |  | 0.4 | mA |
| $1_{1 H^{\ddagger}}$ | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{I}}=2.7 \mathrm{~V}$ |  |  | 20 |  |  | 20 | $\mu \mathrm{A}$ |
| $\mathrm{IIL}^{\ddagger}$ | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{I}}=0.5 \mathrm{~V}$ |  |  | -0.6 |  |  | -0.6 | mA |
| IOS§ | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{O}}=0$ | -100 |  | -225 | -100 |  | -225 | mA |
| ICCH | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$ |  |  | 7 | 11 |  | 7 | 11 | mA |
| ICCL | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$ |  |  | 43 | 68 |  | 43 | 68 | mA |
| ICCZ | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$ |  |  | 9 | 15 |  | 9 | 15 | mA |
| $\mathrm{C}_{\mathrm{i}}$ | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{I}}=2.5 \mathrm{~V}$ or 0.5 V |  | 6 |  |  | 6 |  | pF |
| $\mathrm{C}_{\mathrm{i}}$ | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{O}}=2.5 \mathrm{~V}$ or 0.5 V |  | 16 |  |  | 16 |  | pF |

$\dagger$ All typical values are at $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.
$\ddagger$ For I/O ports, the parameters $\mathrm{I}_{\mathrm{IH}}$ and $\mathrm{I}_{\mathrm{IL}}$ include the off-state output current.
§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

|  |  |  | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}} \\ & \mathrm{~T}_{\mathrm{A}}= \end{aligned}$ | $5 \mathrm{~V},$ | SN54 | T544 | SN74B | T544 | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | MAX | MIN | MAX | MIN | MAX |  |
| $\mathrm{t}_{\text {w }}$ | Pulse duration, $\overline{\mathrm{LEAB}}$ or $\overline{\mathrm{LEBA}}$ low |  | 7 |  | 8 |  | 7 |  | ns |
| $\mathrm{t}_{\text {su }}$ | Setup time, data before $\overline{\mathrm{LEAB}}$ or $\overline{\mathrm{LEBA}} \uparrow$ | High or low | 5 |  | 5.5 |  | 5 |  | ns |
| th | Hold time, data after $\overline{\overline{L E A B}}$ or $\overline{\text { LEBA }} \uparrow$ | High or low | 1 |  | 1 |  | 1 |  | ns |

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}, \mathrm{R}_{\mathrm{L}}=500 \Omega$ (unless otherwise noted) (see Note 2)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \\ & \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C} \end{aligned}$ |  | SN54BCT544 |  | SN74BCT544 |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | MAX | MIN | MAX | MIN | MAX |  |
| tPLH | A or B | B or A | 2.4 | 7.6 | 2.4 | 10.3 | 2.4 | 9.7 | ns |
| tpHL |  |  | 3 | 7.6 | 3 | 8.9 | 3 | 8.5 |  |
| tPLH | $\overline{\text { LEBA }}$ | A | 3.5 | 10.3 | 3.5 | 14.2 | 3.5 | 13.3 | ns |
| tPHL |  |  | 4.8 | 10.2 | 4.8 | 12.7 | 4.8 | 12.3 |  |
| tPLH | $\overline{\text { LEAB }}$ | B | 3.5 | 10.3 | 3.5 | 14.4 | 3.5 | 13.4 | ns |
| tPHL |  |  | 4.8 | 10.3 | 4.8 | 12.8 | 4.8 | 12.4 |  |
| tPZH | $\overline{\mathrm{OE}}$ or $\overline{\mathrm{CE}}$ | A or B | 3 | 10.1 | 3 | 13.1 | 3 | 12.7 | ns |
| tPZL |  |  | 5.1 | 11.8 | 5.1 | 14.2 | 5.1 | 13.9 |  |
| tphz | $\overline{\mathrm{OE}}$ or $\overline{\mathrm{CE}}$ | A or B | 2.8 | 7.5 | 2 | 8.9 | 2.8 | 8.5 | ns |
| tPLZ |  |  | 2.3 | 7.2 | 2.3 | 9 | 2.3 | 8.2 |  |

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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PRODUCT FOLDER | PRODUCT INFO: FEATURES | DESCRIPTION | DATASHEETS | PRICING/AVAILABILITY | APPLICATION NOTES RELATED DOCUMENTS

PRODUCT SUPPORT: TRAINING

## SN54BCT544, Octal Registered Transceivers With 3-State Outputs

 DEVICE STATUS: ACTIVE| PARAMETER NAME | SN54BCT544 |
| :--- | :--- |
| Voltage Nodes (V) | 5 |
| Vcc range (V) | 4.5 to 5.5 |
| Input Level | TL |
| Output Level | TLL |
| No. of Outputs | 8 |
| Logic | Inv |

FEATURES

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- State-of-the-Art BiCMOS Design Significantly Reduces I ccz
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015
- Power-Up High-Impedance State
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Full datasheet in Acrobat PDF: scbs039b.pdf (89 KB) (Updated: 11/01/1993)


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- Implications of Slow or Floating CMOS Inputs (SCBAOO4C - Updated: 02/01/1998)
- Input and Output Characteristics of Digital Integrated Circuits (SDYA010 - Updated: 10/01/1996)
- Live Insertion (SDYA012 - Updated: 10/01/1996)
- Documentation Rules (SAP) And Ordering Information (SZZU001B, 4 KB - Updated: 05/06/1999)
- Logic Selection Guide Second Half 2000 (SDYU001N, 5035 KB - Updated: 04/17/2000)
- MicroStar Junior BGA Design Summary (SCET004, 167 KB - Updated: 07/28/2000)
- More Power In Less Space - Technical Article (SCAU001A, 850 KB - Updated: 03/01/1996)

PRICING/ AVAI LABI LITY
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| $\frac{\text { ORDERABLE }}{\text { DEVICE }}$ | PACKAGE | PINS | $\frac{\text { TEMP }}{(\underline{O} \mathrm{C})}$ | STATUS | BUDGETARY <br> PRICE <br> US $\$ /$ UNIT <br> QTY $=1000+$ | $\frac{\text { PACK }}{\text { QTY }}$ | $\begin{aligned} & \underline{\text { DSCC }} \\ & \text { NUMBER } \end{aligned}$ | PRICING/AVAILABILITY |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SNJ 54BCT544FK | FK | 28 | $\begin{gathered} -55 \\ \text { TO } \\ 125 \\ \hline \end{gathered}$ | ACTIVE | 14.16 | 1 | $\begin{gathered} 5962- \\ 9155401 \mathrm{M} 3 \mathrm{~A} \end{gathered}$ | Check stock or order |
| SNJ 54BCT544JT | IT | 24 | $\begin{gathered} -55 \\ \text { TO } \\ 125 \end{gathered}$ | ACTIVE | 8.80 | 1 | $\begin{gathered} \text { 5962- } \\ 9155401 \text { MLA } \end{gathered}$ | Check stock or order |
| SNJ 54BCT544W | W | 24 | $\begin{gathered} -55 \\ \text { TO } \\ 125 \end{gathered}$ | ACTIVE | 14.16 | 1 |  | Check stock or order |

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